

EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|--------|---|---|------------------|---------|------------------|
| L1 | 5025 | 382/149,145,224,159,100,141,155,181.CQLS. | USPAT | OR | ON | 2009/06/29 11:58 |
| L2 | 4478 | 715/774,835,837,764,841,210,839,762,809,804,973,250,866,708.CQLS. | USPAT | OR | ON | 2009/06/29 12:01 |
| L3 | 1453 | 719/310,315.CQLS. | USPAT | OR | ON | 2009/06/29 12:01 |
| L4 | 355 | 714/E11.21.CQLS. | USPAT | OR | ON | 2009/06/29 12:02 |
| L5 | 1846 | 356/237.1,237.2.CQLS. | USPAT | OR | ON | 2009/06/29 12:03 |
| L6 | 834 | 702/35,1,33.CQLS. | USPAT | OR | ON | 2009/06/29 12:04 |
| L7 | 599018 | (wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 12:29 |
| L8 | 125 | L7 and user adj select\$3 and review and data adj file | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 12:32 |
| L9 | 3 | L8 and input adj user and page and learning adj mode and parameters | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 12:34 |
| L10 | 4 | L8 and input and user and page and learning adj mode and parameters | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 12:37 |
| L11 | 4 | L8 and learning adj mode and parameters | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 12:55 |

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| L12 | 1 | L8 and automatic adj defect and recognition and(detect\$3 or determining)/and(defect or flaw or fault)/and(assign\$3 or test\$3 or evaluat\$3)/and descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 12:58 |
| L13 | 11 | automatic adj defect and recognition and(detect\$3 or determining)/and(defect or flaw or fault)/and(assign\$3 or test\$3 or evaluat\$3)/and descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 12:59 |
| L14 | 10 | L13 and(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 12:59 |
| L15 | 1 | L14 and user adj select\$3 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 13:00 |
| L16 | 1 | L14 and user adj select\$3 and review adj data | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 13:00 |
| L17 | 3 | automatic adj defect and recognition and(detect\$3 or determining)/and(defect or flaw or fault)/and(assign\$3 or test\$3 or evaluat\$3 or accept\$3)and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or cod or camera)and (illumination or source or light or optimal adj intensity or light adj intensity) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 13:12 |
| L18 | 3 | automatic adj defect and recognition and(detect\$3 or determining)/and(defect or flaw or fault)/and(assign\$3 or test\$3 or evaluat\$3 or accept\$3)and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or cod or camera)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 13:16 |
| L19 | 0 | L18 and(@ad<"20030712" or @rlad<"20030712" or @prad<"20030712" or @ptad<"20030712") | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 13:17 |
| L21 | 781 | L1 and(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | USPAT | OR | ON | 2009/06/29 13:19 |
| L22 | 3 | L21 and user adj select\$3 and review and data adj file | USPAT | OR | ON | 2009/06/29 13:19 |

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| L23 | 27 | L21 and user adj select\$3 and review and(storage or stored or memory or data adj file) | USPAT | OR | ON | 2009/06/29 13:20 |
| L24 | 0 | L23 and input and user and page and learning adj mode and parameters | USPAT | OR | ON | 2009/06/29 13:21 |
| L26 | 0 | L23 and automatic adj defect and recognition and(detected\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3)and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or ccd or camera)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 13:23 |
| L27 | 0 | L23 and automatic adj defect and recognition and(detected\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3)and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or ccd or camera)and (illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 13:24 |
| L28 | 2 | L23 and automatic adj defect and recognition and(detected\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3) | USPAT | OR | ON | 2009/06/29 13:25 |
| L29 | 2 | L28 and(@ad<"20030712" or @rad<"20030712" or @prad<"20030712" or @ptad<"20030712") | USPAT | OR | ON | 2009/06/29 13:28 |
| L30 | 0 | L28 and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or ccd or camera)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 13:32 |
| L31 | 0 | L28 and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or ccd or camera)and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 13:43 |
| L32 | 0 | L28 and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or ccd or camera)and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast)and(detected\$3 or determining)and(defect or flaw or fault) | USPAT | OR | ON | 2009/06/29 13:46 |
| L33 | 18 | L2 and(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | USPAT | OR | ON | 2009/06/29 13:48 |
| L34 | 4 | L33 and user adj select\$3 and review and(storage or stored or memory or data adj file) | USPAT | OR | ON | 2009/06/29 13:48 |
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| L37 | 2 | L3 and(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | USPAT | OR | ON | 2009/06/29 13:53 |
| L38 | 0 | L37 and automatic adj defect and recognition and(detected\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3) | USPAT | OR | ON | 2009/06/29 13:55 |

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| L39 | 0 | L37 and user adj select\$3 and review and(storage or stored or memory or data adj file) | USPAT | OR | ON | 2009/06/29 13:56 |
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| L41 | 2 | L3 and(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | USPAT | OR | ON | 2009/06/29 13:59 |
| L42 | 1 | L4 and(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | USPAT | OR | ON | 2009/06/29 13:59 |
| L43 | 0 | L42 and automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3) | USPAT | OR | ON | 2009/06/29 13:59 |
| L44 | 0 | L42 and user adj select\$3 and review and(storage or stored or memory or data adj file) | USPAT | OR | ON | 2009/06/29 13:59 |
| L45 | 0 | L42 and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or ccd or camera)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 14:00 |
| L46 | 733 | L5 and(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | USPAT | OR | ON | 2009/06/29 14:01 |
| L47 | 5 | L46 and automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3) | USPAT | OR | ON | 2009/06/29 14:01 |
| L48 | 0 | L47 and user adj select\$3 and review and(storage or stored or memory or data adj file) | USPAT | OR | ON | 2009/06/29 14:01 |
| L49 | 0 | L47 and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or ccd or camera)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 14:01 |
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| L51 | 0 | L47 and user adj select\$3 and review and(storage or stored or memory or data adj file) | USPAT | OR | ON | 2009/06/29 14:03 |
| L52 | 599018 | (wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 14:04 |
| L53 | 83 | defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 14:04 |

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| L54 | 19 | L53 and (wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/06/29 14:04 |
| L55 | 12 | L54 and @ad<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/06/29 14:04 |
| L56 | 3 | L55 and descriptor | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/06/29 14:04 |
| L57 | 685554 | L56 and select\$3 and review and data file | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/06/29 14:04 |
| L58 | 18 | L53 and select\$3 and review and data adj file | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/06/29 14:04 |
| L59 | 17 | L58 and parameters | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/06/29 14:04 |
| L60 | 2 | L52 and L53 and L57 and L59 | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/06/29 14:04 |
| L61 | 0 | L60 and @ad<"20030712" | USPAT | OR | ON | 2009/06/29 14:04 |
| L63 | 129 | L6 and (wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | USPAT | OR | ON | 2009/06/29 14:06 |
| L64 | 4 | L63 and user adj select\$3 and review and (storage or stored or memory or data adj file) | USPAT | OR | ON | 2009/06/29 14:06 |
| L65 | 0 | L64 and select\$3 adj (wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) and (capturing or pictures or cod or camera) and align\$4 and (illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 14:07 |

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|-----|--------|---|---|----|----|---------------------|
| L66 | 0 | L64 and automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3) | USPAT | OR | ON | 2009/06/29 14:08 |
| L67 | 3 | L64 and(@ad<"20030712" or @lad<"20030712" or @prad<"20030712" or @ptad<"20030712") | USPAT | OR | ON | 2009/06/29 14:09 |
| L68 | 0 | L67 and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or cod or camera)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 14:23 |
| L69 | 1 | L63 and automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3) | USPAT | OR | ON | 2009/06/29 14:26 |
| L70 | 0 | L69 and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or cod or camera)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 14:26 |
| L71 | 0 | L69 and user adj select\$3 and review and(storage or stored or memory or data adj file) | USPAT | OR | ON | 2009/06/29 14:28 |
| L79 | 1 | ((wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) and user adj select\$3 and review and data adj file and input and user and page and learning adj mode).dm. | US-PGPUB | OR | ON | 2009/06/29 14:51 |
| L81 | 1 | L69 and automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3 or accept\$3) | USPAT | OR | ON | 2009/06/29 14:55 |
| L82 | 0 | L81 and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or cod or camera)and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 14:59 |
| L83 | 0 | L81 and select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or cod or camera)and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | USPAT | OR | ON | 2009/06/29 14:59 |
| L84 | 0 | accept\$3 adj select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or cod or camera)and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3)and align\$4 and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 15:14 |
| L85 | 0 | accept\$3 adj select\$3 adj(wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1)and(capturing or pictures or cod or camera)and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3)and(illumination or source or light or optimal adj intensity or light adj intensity or brightness or contrast) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/06/29 15:15 |
| S1 | 571947 | (wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:27 |

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| S2 | 1 | S1 and automatic and defect adj classification and teaching and knowledge adj based adj database | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:29 |
| S3 | 1 | automatic and defect adj classification and teaching and knowledge adj based adj database | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:30 |
| S4 | 1 | S1 and defect adj classification and teaching and knowledge adj based adj database | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:30 |
| S5 | 1 | defect adj classification and teaching and knowledge adj based adj database | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:30 |
| S6 | 2 | defect adj classification and knowledge adj based adj database | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:31 |
| S7 | 82 | defect and classification and knowledge adj database | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:31 |
| S8 | 19 | S7 and (water\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:31 |
| S9 | 17 | S8 and(@ad<"20030712" or @rlad<"20030712" or @prad<"20030712" or @ptad<"20030712") | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:36 |
| S10 | 12 | S9 and @ad<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:36 |

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| S11 | 24 | ((DIRK) near2 (SOENKSEN)).INV. | US-PGPUB; USPAT | OR | ON | 2008/12/05 11:36 |
| S12 | 11 | ((RALF) near2 (FRIEDRICH)).INV. | US-PGPUB; USPAT | OR | ON | 2008/12/05 11:37 |
| S13 | 1 | ((ANDREAS) near2 (DRAEGER)).INV. | US-PGPUB; USPAT | OR | ON | 2008/12/05 11:37 |
| S14 | 2 | ((DETLEF) near2 (SCHUPP)).INV. | US-PGPUB; USPAT | OR | ON | 2008/12/05 11:37 |
| S16 | 2 | ((THIN) near2 (~VAN LUU)).INV. | US-PGPUB; USPAT | OR | ON | 2008/12/05 11:39 |
| S17 | 3 | ((WOLFGANG) near2 (LANGER)).INV. | US-PGPUB; USPAT | OR | ON | 2008/12/05 11:39 |
| S18 | 0 | S11 and defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:40 |
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| S20 | 0 | S11 and defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:41 |
| S21 | 0 | S12 and defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:41 |
| S22 | 0 | S13 and defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:43 |
| S23 | 3 | S10 and descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:46 |

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| S24 | 638382 | S23 and select\$3 and review and data file | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 11:47 |
| S25 | 0 | S23 and select\$3 and review and data adj file | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 11:47 |
| S26 | 18 | S7 and select\$3 and review and data adj file | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 11:48 |
| S27 | 0 | S26 and parameters and learning adj node | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 11:49 |
| S28 | 0 | S26 and parameters and learning adj mode | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 11:49 |
| S29 | 17 | S26 and parameters | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 11:49 |
| S30 | 2 | S1 and S7 and S24 and S29 | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 11:56 |
| S31 | 2 | S30 and @ad<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 11:56 |
| S32 | 18 | S7 and S26 | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 11:57 |

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| S33 | 16 | S32 and @ad<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 11:58 |
| S34 | 20 | S1 and automatic and defect adj recognition | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:00 |
| S35 | 638382 | S34 and select\$3 and review and data file | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:01 |
| S36 | 4 | S34 and descriptor | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:33 |
| S37 | 1 | S34 and learning adj mode | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:34 |
| S38 | 0 | S37 and @ad<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:34 |
| S39 | 16 | S34 and @ad<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:35 |
| S40 | 0 | S39 and learning adj mode | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:35 |
| S41 | 2 | S39 and learning | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:35 |

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| S43 | 0 | S42 and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 12:40 |
| S44 | 0 | S42 and learning near mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 12:40 |
| S45 | 0 | S42 and learning near3 mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 12:40 |
| S46 | 11 | S42 and descriptor | US-PGPUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 12:40 |
| S47 | 598 | S1 and select\$3 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 12:44 |
| S48 | 340 | S47 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 12:44 |
| S49 | 1 | S48 and input and user and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 12:45 |
| S50 | 1 | S48 and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 12:46 |

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| S51 | 4 | S48 and alignment adj procedure | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 12:46 |
| S52 | 0 | S8 and automatic adj defect and recognition and(detect\$3 or determining)same (defect or flaw or fault)same(assign\$3 or test\$3 or evaluat\$3)same descriptor | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:02 |
| S53 | 0 | S48 and automatic adj defect and recognition and(detect\$3 or determining)same (defect or flaw or fault)same(assign\$3 or test\$3 or evaluat\$3)same descriptor | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:02 |
| S54 | 1 | automatic adj defect and recognition and(detect\$3 or determining)same (defect or flaw or fault)same(assign\$3 or test\$3 or evaluat\$3)same descriptor | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:02 |
| S55 | 11 | automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3)and descriptor | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:03 |
| S56 | 5 | S55 and @ad<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:03 |
| S57 | 1 | S56 and learning adj mode | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:03 |
| S58 | 0 | S57 and edit adj recipe | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:05 |
| S59 | 0 | S57 and edit | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/05 13:05 |

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| S60 | 0 | S67 and memory adj circuits | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 13:07 |
| S61 | 1 | S67 and circuits | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 13:07 |
| S62 | 0 | S61 and logic adj circuits | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 13:08 |
| S63 | 0 | S61 and blank adj wafer\$1 | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 13:08 |
| S64 | 1 | S66 and learning adj mode | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/05 14:02 |
| S65 | 571947 | (wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/06 11:12 |
| S66 | 2 | S65 and select\$3 and review adj data adj file | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/06 11:13 |
| S67 | 2 | S65 and review adj data adj file | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/06 11:13 |
| S68 | 638 | S65 and review and data adj file | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/06 11:14 |

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| S69 | 134 | S65 and review same data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:14 |
| S70 | 0 | S69 and defect and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:15 |
| S71 | 0 | S69 and classification and knowledge adj database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:15 |
| S72 | 1 | S69 and classification and knowledge near3 database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:15 |
| S73 | 11 | S68 and classification and knowledge near3 database | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:15 |
| S74 | 5 | S73 and @ad<"20030712" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:16 |
| S75 | 5 | S74 and review and data adj file | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:16 |
| S76 | 1 | S75 and (user or operator or human)and page and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:17 |
| S77 | 1 | S75 and (user or operator or human)and learning adj mode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:17 |

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| S78 | 9 | S68 and (detect\$3 or determining) and (defect or fault or flaw) and classification and knowledge near3 database | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:19 |
| S79 | 13 | learning and (knowledge-based or knowledge adj based) and database and automatic and defect adj classification | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:21 |
| S80 | 10 | S79 and @ad<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:21 |
| S81 | 0 | S80 and review and data adj file | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:21 |
| S82 | 1 | S80 and data adj file | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:22 |
| S83 | 8 | S80 and (wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:24 |
| S84 | 8 | S83 and @ad<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:24 |
| S85 | 6 | S84 and descriptor | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:43 |
| S86 | 5 | S84 and descriptor adj (defect or fault or flaw) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/06 11:46 |

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| S87 | 573639 | (wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/17 19:04 |
| S88 | 19 | S87 and defect and classification and knowledge adj database | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/17 19:05 |
| S89 | 640949 | S88 and select\$3 and review and data file | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/17 19:05 |
| S90 | 2 | S88 and select\$3 and review and data adj file | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/17 19:05 |
| S91 | 8 | S87 and display adj thumbnails | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/17 19:07 |
| S92 | 2 | S91 and @ad<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/17 19:07 |
| S93 | 0 | S92 and descriptor | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/17 19:15 |
| S94 | 8 | S91 and parameters | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/17 19:27 |
| S95 | 1 | S94 and automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3) | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/17 19:29 |

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| S96 | 2 | S92 and display adj thumbnails | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:30 |
| S97 | 2 | S96 and parameters | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:30 |
| S98 | 0 | S97 and circuits | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:31 |
| S99 | 0 | S97 and defect and (classification or classifier or classify) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:32 |
| S100 | 0 | S97 and(classification or classifier or classify or grouping) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:33 |
| S101 | 0 | S97 and intensity | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:33 |
| S102 | 2 | S97 and (intensity or contrast or brightness) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:34 |
| S103 | 2 | S102 and(illumination or source or light) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:34 |
| S104 | 2 | S103 and(blank adj wafer\$1 or wafer\$1) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:36 |

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|------|---|--|---|----|----|---------------------|
| S105 | 2 | S104 and (polymer or layer or oxide adj layer or contact or metal) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:38 |
| S106 | 0 | S105 and lens | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:39 |
| S107 | 0 | S105 and focus | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:39 |
| S108 | 0 | S105 and magnificat\$3 | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:40 |
| S109 | 2 | S105 and @ack<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:40 |
| S110 | 2 | S109 and select\$3 adj recipe | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/17 19:41 |
| S111 | 2 | "6973209".pn. | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:40 |
| S112 | 0 | S111 and alignment | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:40 |
| S113 | 1 | S111 and algn\$3 | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 15:40 |

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|------|---|--|---|----|----|---------------------|
| S114 | 0 | S111 and align\$3 same light | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/19 15:41 |
| S115 | 1 | S111 and align\$3 and(light or source or illuminat\$3) | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/19 15:41 |
| S116 | 1 | S115 and adjusting | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/19 15:42 |
| S117 | 0 | S116 and optimal adj intensity | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/19 15:42 |
| S118 | 1 | S116 and optimal | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/19 15:42 |
| S119 | 0 | S118 and intensity | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/19 15:42 |
| S120 | 1 | S118 and parameters | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/19 15:43 |
| S121 | 1 | S120 and algorithm | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/19 15:46 |
| S122 | 1 | S121 and automatic | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/19 15:47 |

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| S123 | 0 | S122 and intensity | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/19 15:47 |
| S124 | 1 | S122 and (intensity or contrast or brightness) | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/19 15:47 |
| S125 | 0 | S124 and text adj image\$1 | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/19 15:48 |
| S126 | 0 | S124 and text | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/19 15:48 |
| S127 | 1 | S124 and recipe | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/19 15:49 |
| S128 | 0 | S127 and review | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/19 15:49 |
| S129 | 1 | S127 and dictionary | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/19 15:49 |
| S130 | 1 | S129 and registered | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/19 15:50 |
| S131 | 1 | S130 and drag | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/19 15:51 |

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|------|----|--|---|----|----|---------------------|
| S132 | 82 | defect and classification and knowledge adj database | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 16:09 |
| S133 | 18 | S132 and select\$3 and review and data adj file | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 16:09 |
| S134 | 16 | S133 and @ad< "20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 16:09 |
| S135 | 0 | S132 and select\$3 same review adj data | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 16:13 |
| S136 | 5 | S132 and review adj data | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 16:13 |
| S137 | 3 | S136 and @ad< "20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 16:14 |
| S138 | 1 | S137 and descriptors | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 16:19 |
| S139 | 0 | S137 and defect adj descriptors | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/19 16:20 |
| S140 | 82 | defect and classification and knowledge adj database | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:44 |

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|------|-----|--|---|----|----|---------------------|
| SI41 | 5 | SI40 and review adj data | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:44 |
| SI42 | 3 | SI41 and @ad<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:44 |
| SI43 | 2 | SI42 and(wafer\$1 or semicondutor\$1 or chip\$1 or subtrat\$1) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:45 |
| SI44 | 3 | "6408219".pn. | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:46 |
| SI45 | 1 | SI44 and review adj data | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:47 |
| SI46 | 1 | SI44 and select\$3 | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:48 |
| SI47 | 732 | select\$3 same review adj data | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:50 |
| SI48 | 62 | SI47 and(wafer\$1 or semicondutor\$1 or chip\$1 or subtrat\$1) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:50 |
| SI49 | 0 | SI48 and defect and classification and knowledge adj database | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:50 |

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|------|----|---|--|----|----|---------------------|
| SI50 | 0 | SI48 and classification and knowledge adj database | US-PG&PUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:50 |
| SI51 | 14 | SI48 and @ack<"20030712" | US-PG&PUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:51 |
| SI52 | 0 | SI51 and display adj thumbnails | US-PG&PUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:51 |
| SI53 | 0 | SI51 and display and thumbnails | US-PG&PUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:52 |
| SI54 | 0 | SI51 and thumbnails | US-PG&PUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 11:52 |
| SI55 | 0 | SI51 and automatic and defect adj recognition | US-PG&PUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 12:12 |
| SI56 | 0 | SI51 and select\$3 adj recipe | US-PG&PUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 12:13 |
| SI57 | 1 | SI51 and align\$3 and(light or source or illuminat\$3) | US-PG&PUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 12:13 |
| SI58 | 0 | SI57 and(user or operator or human)and page and learning adj mode | US-PG&PUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 12:16 |

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|------|--------|--|---|----|----|---------------------|
| SI59 | 0 | SI57 and descriptors | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 12:16 |
| SI60 | 0 | SI57 and parameters | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/30 12:36 |
| SI61 | 11 | automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3)and descriptor | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 15:58 |
| SI62 | 5 | SI61 and @ad< "20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 15:58 |
| SI63 | 1 | SI62 and learning adj mode | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 15:58 |
| SI64 | 0 | SI63 and memory adj circuits | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 15:58 |
| SI65 | 575216 | (wafer\$1 or semiconductor\$1 or chip\$1 or substrat\$1) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 15:58 |
| SI66 | 10 | SI65 and automatic adj defect and recognition and(detect\$3 or determining)and(defect or flaw or fault)and(assign\$3 or test\$3 or evaluat\$3)and descriptor | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 15:59 |
| SI67 | 643423 | SI66 and select\$3 and review and data file | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 15:59 |

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| SI68 | 1 | SI66 and select\$3 and review and data adj file | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/31 16:00 |
| SI69 | 0 | SI68 and @ad<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/31 16:00 |
| SI70 | 1 | SI66 and memory adj circuits | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/31 16:00 |
| SI71 | 0 | SI70 and @ad<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/31 16:01 |
| SI72 | 4 | SI66 and @ad<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/31 16:01 |
| SI73 | 0 | SI72 and memory adj circuits | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/31 16:01 |
| SI74 | 7745 | SI65 and memory adj circuits | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/31 16:01 |
| SI75 | 2341 | SI74 and parameters | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/31 16:01 |
| SI76 | 775 | SI75 and logic adj circuits | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2008/12/31 16:02 |

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|------|-------|----------------------------|---|----|----|---------------------|
| S177 | 9 | S176 and blank adj wafer | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:02 |
| S178 | 8 | S177 and @ad< "20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:03 |
| S179 | 0 | S178 and resist | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:03 |
| S180 | 0 | S178 and photo adj resist | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:03 |
| S181 | 0 | S178 and polymer adj layer | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:04 |
| S182 | 51765 | polymer adj layer | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:04 |
| S183 | 33269 | S182 and @ad< "20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:04 |
| S184 | 2388 | S183 and oxide adj layer | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:05 |
| S185 | 1703 | S184 and contact | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:05 |

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|------|-------|--|---|----|----|---------------------|
| SI86 | 16332 | SI83 and contact | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:05 |
| SI87 | 10 | SI86 and metal adj later | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:06 |
| SI88 | 1 | SI87 and parameters | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:06 |
| SI89 | 1 | SI88 and @ack<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:06 |
| SI90 | 1 | SI89 and(intensity or contrast or brightness) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:07 |
| SI91 | 0 | SI90 and align\$3 and(light or source or illuminat\$3) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:07 |
| SI92 | 1 | SI90 and(light or source or illuminat\$3) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:07 |
| SI93 | 0 | SI92 and magnificat\$3 | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:08 |
| SI94 | 0 | SI92 and lens | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:08 |

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| S195 | 0 | S192 and histogram | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:08 |
| S196 | 0 | S195 and focus\$3 | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/12/31 16:12 |
| S197 | 51832 | polymer adj layer | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:04 |
| S198 | 33269 | S197 and @ad<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:04 |
| S199 | 16332 | S198 and contact | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:04 |
| S200 | 10 | S199 and metal adj later | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:04 |
| S201 | 1 | S200 and parameters | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:04 |
| S202 | 1 | S201 and @ad<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:04 |
| S203 | 1 | S202 and(intensity or contrast or brightness) | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:04 |

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| S204 | 1 | S203 and(light or source or illuminat\$3) | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/01/02 14:04 |
| S205 | 0 | S204 and metal adj layer | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/01/02 14:05 |
| S206 | 1 | S204 and metal | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/01/02 14:06 |
| S207 | 0 | S206 and bright adj field | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/01/02 14:07 |
| S208 | 0 | S206 and bright | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/01/02 14:07 |
| S209 | 1 | S206 and (UV or DUV) | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/01/02 14:08 |
| S210 | 0 | S209 and lens | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/01/02 14:08 |
| S211 | 0 | S209 and intensity | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/01/02 14:09 |
| S212 | 1 | S209 and contrast | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/01/02 14:10 |

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| S213 | 0 | S212 and histogram | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/01/02 14:10 |
| S214 | 795256 | select\$3 and review and data file | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/01/02 14:12 |
| S215 | 2665 | S214 and polymer adj layer | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/01/02 14:13 |
| S216 | 12 | S215 and bright adj field | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/01/02 14:13 |
| S217 | 9 | S216 and (UV or DUV) | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/01/02 14:13 |
| S218 | 3 | S217 and @ad<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/01/02 14:13 |
| S219 | 3 | S218 and intensity | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/01/02 14:13 |
| S220 | 0 | S219 and histogram | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/01/02 14:14 |
| S221 | 0 | S219 and metal adj layer | US-PGRUB; USPAT; EPO; JPO; DERWENT; JBM_TDB | OR | ON | 2009/01/02 14:14 |

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|------|---|-------------------------|---|----|----|---------------------|
| S222 | 0 | S219 and lens | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:14 |
| S223 | 4 | S216 and lens | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:15 |
| S224 | 0 | S223 and @ad<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:15 |
| S225 | 0 | S223 and @ad<"20030712" | US-PGRUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2009/01/02 14:15 |

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